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| Notice of References Cited | Application/Control No. 09/872,736 | Applicant(s)/Patent Under Reexamination OVERTON ET AL. | |
| | Examiner Michael S. A. Delgado | Art Unit 2144 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-------------------------|----------------|
| | A | US-6,463,454 | 10-2002 | Lumelsky et al. | 718/105 |
| | B | US-6,466,980 | 10-2002 | Lumelsky et al. | 709/226 |
| | C | US-6,578,068 | 06-2003 | Bowman-Amuah, Michel K. | 709/203 |
| | D | US-6,711,408 | 03-2004 | Raith, Alex Krister | 455/440 |
| | E | US-6,438,652 | 08-2002 | Jordan et al. | 711/120 |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
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| | P | | | | | |
| | Q | | | | | |
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| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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